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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	51
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 15x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f302r6t6

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3 Functional overview

3.1 ARM[®] Cortex[®]-M4 core with FPU, embedded Flash and SRAM

The ARM[®] Cortex[®]-M4 processor with FPU is the latest generation of ARM processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced response to interrupts.

The ARM[®] Cortex[®]-M4 32-bit RISC processor with FPU features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

The processor supports a set of DSP instructions which allow efficient signal processing and complex algorithm execution. Its single-precision FPU speeds up software development by using metalanguage development tools while avoiding saturation.

With its embedded ARM core, the STM32F302x6/8 family is compatible with all ARM tools and software.

Figure 1 shows the general block diagram of the STM32F302x6/8 family devices.

3.2 Memories

3.2.1 Embedded Flash memory

All STM32F302x6/8 devices feature up to 64 Kbytes of embedded Flash memory available for storing programs and data. The Flash memory access time is adjusted to the CPU clock frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states above).

3.2.2 Embedded SRAM

STM32F302x6/8 devices feature 16 Kbytes of embedded SRAM.

3.3 Boot modes

At startup, BOOT0 pin and BOOT1 option bit are used to select one of three boot options:

- Boot from user Flash
- Boot from system memory
- Boot from embedded SRAM

The boot loader is located in system memory. It is used to reprogram the Flash memory by using USART1 (PA9/PA10), USART2 (PA2/PA3) or USB (PA11/PA12) through DFU (device firmware upgrade).

3.5.3 Voltage regulator

The regulator has three operation modes: main (MR), low-power (LPR), and power-down.

- The MR mode is used in the nominal regulation mode (Run)
- The LPR mode is used in Stop mode.
- The power-down mode is used in Standby mode: the regulator output is in high impedance, and the kernel circuitry is powered down thus inducing zero consumption.

The voltage regulator is always enabled after reset. It is disabled in Standby mode.

3.5.4 Low-power modes

The STM32F302x6/8 supports three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- Sleep mode
In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.
- Stop mode
Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low-power mode.
The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the 16 external lines, the PVD output, the USB wakeup, the RTC alarm, COMPx, I2C or USARTx.
- Standby mode
The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.
The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin, or an RTC alarm occurs.

Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.

3.6 Interconnect matrix

Several peripherals have direct connections between them. This allows autonomous communication between peripherals, saving CPU resources thus power supply consumption. In addition, these hardware connections allow fast and predictable latency.

3.11.3 V_{BAT} battery voltage monitoring

This embedded hardware feature allows the application to measure the V_{BAT} battery voltage using the internal ADC channel ADC1_IN17. As the V_{BAT} voltage may be higher than V_{DDA} , and thus outside the ADC input range, the V_{BAT} pin is internally connected to a bridge divider by 2. As a consequence, the converted digital value is half the V_{BAT} voltage.

3.12 Digital-to-analog converter (DAC)

One 12-bit buffered DAC channel (DAC1_OUT1) can be used to convert digital signals into analog voltage signal outputs. The chosen design structure is composed of integrated resistor strings and an amplifier in inverting configuration.

This digital interface supports the following features:

- One DAC output channel
- 8-bit or 12-bit monotonic output
- Left or right data alignment in 12-bit mode
- Synchronized update capability
- Noise-wave generation
- Triangular-wave generation
- DMA capability
- External triggers for conversion

3.13 Operational amplifier (OPAMP)

The STM32F302x6/8 devices embed one operational amplifier with external or internal follower routing and PGA capability (or even amplifier and filter capability with external components). When the operational amplifier is selected, an external ADC channel is used to enable output measurement.

The operational amplifier features:

- 8.2 MHz bandwidth
- 0.5 mA output capability
- Rail-to-rail input/output
- In PGA mode, the gain can be programmed to be 2, 4, 8 or 16.

3.18 Universal synchronous/asynchronous receiver transmitter (USART)

The STM32F302x6/8 devices have three embedded universal synchronous receiver transmitters (USART1, USART2 and USART3).

The USART interfaces are able to communicate at speeds of up to 9 Mbit/s.

All USARTs support hardware management of the CTS and RTS signals, multiprocessor communication mode, single-wire half-duplex communication mode and synchronous mode.

USART1 supports SmartCard mode, IrDA SIR ENDEC, LIN Master capability and autobaudrate detection.

All USART interfaces can be served by the DMA controller.

Refer to [Table 7](#) for the features available in all USARTs interfaces.

Table 7. USART features

USART modes/features ⁽¹⁾	USART1	USART2	USART3
Hardware flow control for modem	X	X	X
Continuous communication using DMA	X	X	X
Multiprocessor communication	X	X	X
Synchronous mode	X	X	X
SmartCard mode	X	-	-
Single-wire half-duplex communication	X	X	X
IrDA SIR ENDEC block	X	-	-
LIN mode	X	-	-
Dual clock domain and wakeup from Stop mode	X	-	-
Receiver timeout interrupt	X	-	-
Modbus communication	X	-	-
Auto baud rate detection	X	-	-
Driver Enable	X	X	X

1. X = supported.

3.19 Serial peripheral interfaces (SPI)/Inter-integrated sound interfaces (I2S)

Two SPI interfaces (SPI2 and SPI3) allow communication up to 18 Mbit/s in slave and master modes in full-duplex and simplex modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

Two standard I2S interfaces (multiplexed with SPI2 and SPI3) are available, that can be operated in master or slave mode. These interfaces can be configured to operate with 16/32 bit resolution, as input or output channels. Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I2S interfaces is/are configured in master

Table 9. Capacitive sensing GPIOs available on STM32F302x6/8 devices

Group	Capacitive sensing signal name	Pin name
1	TSC_G1_IO1	PA0
	TSC_G1_IO2	PA1
	TSC_G1_IO3	PA2
	TSC_G1_IO4	PA3
2	TSC_G2_IO1	PA4
	TSC_G2_IO2	PA5
	TSC_G2_IO3	PA6
	TSC_G2_IO4	PA7
3	TSC_G3_IO1	PC5
	TSC_G3_IO2	PB0
	TSC_G3_IO3	PB1
	TSC_G3_IO4	PB2
4	TSC_G4_IO1	PA9
	TSC_G4_IO2	PA10
	TSC_G4_IO3	PA13
	TSC_G4_IO4	PA14
5	TSC_G5_IO1	PB3
	TSC_G5_IO2	PB4
	TSC_G5_IO3	PB6
	TSC_G5_IO4	PB7
6	TSC_G6_IO1	PB11
	TSC_G6_IO2	PB12
	TSC_G6_IO3	PB13
	TSC_G6_IO4	PB14

Table 10. No. of capacitive sensing channels available on STM32F302x6/8 devices

Analog I/O group	Number of capacitive sensing channels		
	STM32F302Rx	STM32F302Cx	STM32F302Kx
G1	3	3	3
G2	3	3	3
G3	3	2	1
G4	3	3	3
G5	3	3	3

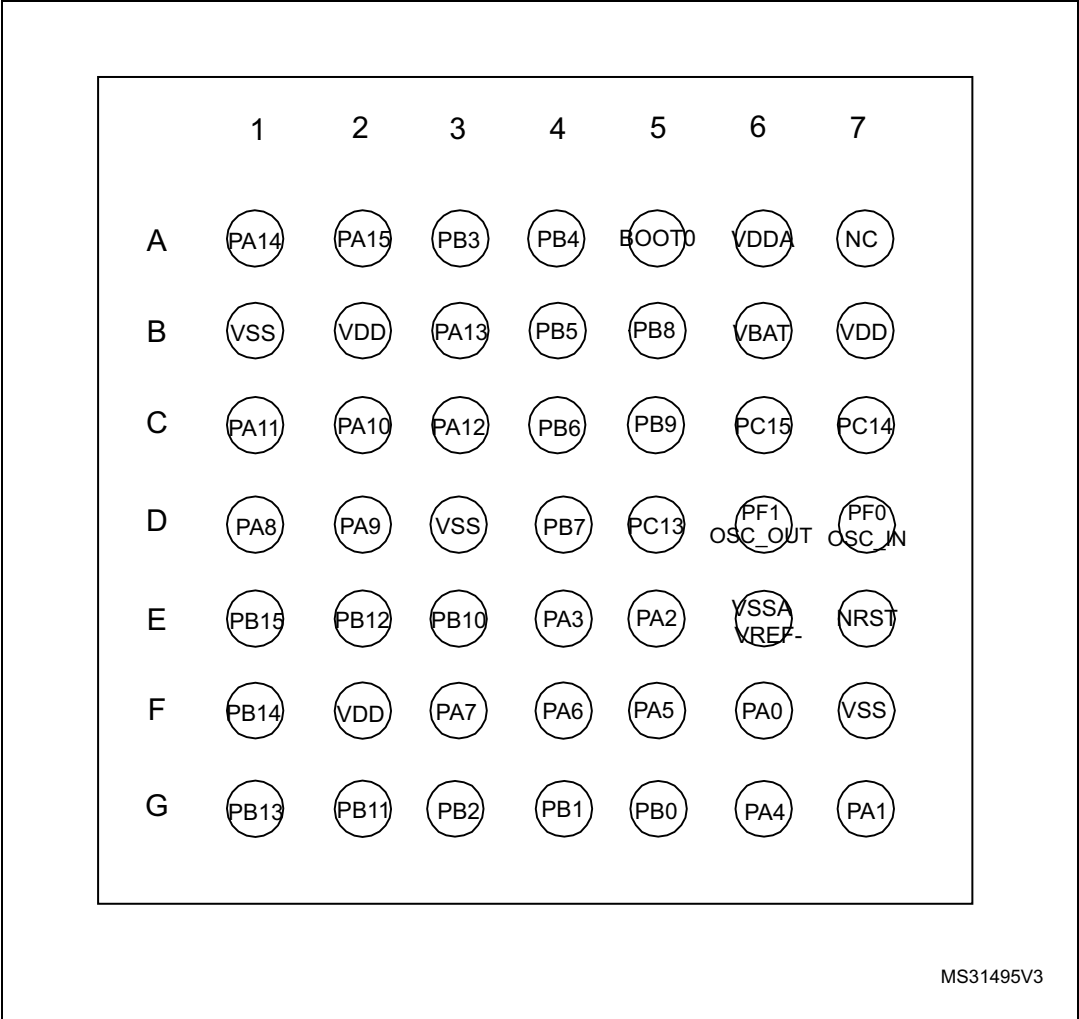
3.24 Development support

3.24.1 Serial wire JTAG debug port (SWJ-DP)

The ARM SWJ-DP Interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target.

The JTAG TMS and TCK pins are shared respectively with SWDIO and SWCLK and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

Figure 7. STM32F302x6/8 WLCSP49 ballout



- 1. The above figure shows the package top view.
- 2. NC: Not connected.

Table 13. Alternate functions for Port A

Port & pin name																
	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS_AF	TIM2/TIM15/TIM16/TIM17/EVENT	I2C3/TIM1/TIM2/TIM15	I2C3/TIM15/TSC	I2C1/I2C2/TIM1/TIM16/TIM17	SPI2/I2S2/SPI3/I2S3/Infrared	SPI2/I2S2/SPI3/I2S3/TIM1/Infrared	USART1/USART2/USART3/CAN/GPCOMP6	I2C3/GPCOMP2/GPCOMP4/GPCOMP6	CAN/TIM1/TIM15	TIM2/TIM17	TIM1	TIM1	-	-	EVENT
PA0	-	TIM2_CH1/TIM2_ETR	-	TSC_G1_IO1	-	-	-	USART2_CTS	-	-	-	-	-	-	-	EVENT OUT
PA1	RTC_REFIN	TIM2_CH2	-	TSC_G1_IO2	-	-	-	USART2_RTS_D	-	TIM15_CH1N	-	-	-	-	-	EVENT OUT
PA2	-	TIM2_CH3	-	TSC_G1_IO3	-	-	-	USART2_TX	COMP2_OUT	TIM15_CH1	-	-	-	-	-	EVENT OUT
PA3	-	TIM2_CH4	-	TSC_G1_IO4	-	-	-	USART2_RX	-	TIM15_CH2	-	-	-	-	-	EVENT OUT
PA4	-	-	-	TSC_G2_IO1	-	-	SPI3_NSS/I2S3_WS	USART2_CK	-	-	-	-	-	-	-	EVENT OUT
PA5	-	TIM2_CH1/TIM2_ETR	-	TSC_G2_IO2	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
PA6	-	TIM16_CH1	-	TSC_G2_IO3	-	-	TIM1_BKIN	-	-	-	-	-	-	-	-	EVENT OUT
PA7	-	TIM17_CH1	-	TSC_G2_IO4	-	-	TIM1_CH1N	-	-	-	-	-	-	-	-	EVENT OUT
PA8	MCO	-	-	I2C3_SCL	I2C2_SMBAL	I2S2_MCK	TIM1_CH1	USART1_CK	-	-	-	-	-	-	-	EVENT OUT



Table 13. Alternate functions for Port A (continued)

Port & pin name																
	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS_AF	TIM2/TIM15/TIM16/TIM17/EVENT	I2C3/TIM1/TIM2/TIM15	I2C3/TIM15/TSC	I2C1/I2C2/TIM1/TIM16/TIM17	SPI2/I2S2/SPI3/I2S3/Infrared	SPI2/I2S2/SPI3/I2S3/Infrared	USART1/USART2/USART3/CAN/GPCOMP6	I2C3/GPCOMP2/GPCOMP4/GPCOMP6	CAN/TIM1/TIM15	TIM2/TIM17	TIM1	TIM1	-	-	EVENT
PA9	-	-	I2C3_SMBAL	TSC_G4_IO1	I2C2_SCL	I2S3_MCK	TIM1_CH2	USART1_TX	-	TIM15_BKIN	TIM2_CH3	-	-	-	-	EVENT OUT
PA10	-	TIM17_BKIN		TSC_G4_IO2	I2C2_SDA	SPI2_MISO/I2S2ext_SD	TIM1_CH3	USART1_RX	COMP6_OUT	-	TIM2_CH4	-	-	-	-	EVENT OUT
PA11	-	-	-	-	-	SPI2_MOSI/I2S2_SD	TIM1_CH1N	USART1_CTS	-	CAN_RX	-	TIM1_CH4	TIM1_BKIN2	-	-	EVENT OUT
PA12	-	TIM16_CH1	-	-	-	I2SCKIN	TIM1_CH2N	USART1_RTS_DE	COMP2_OUT	CAN_TX	-	TIM1_ETR	-	-	-	EVENT OUT
PA13	SWDAT-JTMS	TIM16_CH1N	-	TSC_G4_IO3	-	IR-OUT	-	USART3_CTS	-	-	-	-	-	-	-	EVENT OUT
PA14	SWCLK-JTCK		-	TSC_G4_IO4	I2C1_SDA	-	TIM1_BKIN	USART2_TX	-	-	-	-	-	-	-	EVENT OUT
PA15	JTDI	TIM2_CH1/TIM2_ETR	-	TSC_SYNC	I2C1_SCL	-	SPI3_NSS/I2S3_WS	USART2_RX	-	TIM1_BKIN	-	-	-	-	-	EVENT OUT

I/O system current consumption

The current consumption of the I/O system has two components: static and dynamic.

I/O static current consumption

All the I/Os used as inputs with pull-up generate current consumption when the pin is externally held low. The value of this current consumption can be simply computed by using the pull-up/pull-down resistors values given in [Table 53: I/O static characteristics](#).

For the output pins, any external pull-down or external load must also be considered to estimate the current consumption.

Additional I/O current consumption is due to I/Os configured as inputs if an intermediate voltage level is externally applied. This current consumption is caused by the input Schmitt trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

Caution: Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

I/O dynamic current consumption

In addition to the internal peripheral current consumption (see [Table 36: Peripheral current consumption](#)), the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the MCU supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DD} \times f_{SW} \times C$$

where

I_{SW} is the current sunk by a switching I/O to charge/discharge the capacitive load

V_{DD} is the MCU supply voltage

f_{SW} is the I/O switching frequency

C is the total capacitance seen by the I/O pin: $C = C_{INT} + C_{EXT} + C_S$

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.

High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 32 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in [Table 41](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 41. HSE oscillator characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min ⁽²⁾	Typ	Max ⁽²⁾	Unit
f_{OSC_IN}	Oscillator frequency	-	4	8	32	MHz
R_F	Feedback resistor	-	-	200	-	k Ω
I_{DD}	HSE current consumption	During startup ⁽³⁾	-	-	8.5	mA
		$V_{DD}=3.3\text{ V}$, $R_m=30\Omega$, $CL=10\text{ pF}@8\text{ MHz}$	-	0.4	-	
		$V_{DD}=3.3\text{ V}$, $R_m=45\Omega$, $CL=10\text{ pF}@8\text{ MHz}$	-	0.5	-	
		$V_{DD}=3.3\text{ V}$, $R_m=30\Omega$, $CL=5\text{ pF}@32\text{ MHz}$	-	0.8	-	
		$V_{DD}=3.3\text{ V}$, $R_m=30\Omega$, $CL=10\text{ pF}@32\text{ MHz}$	-	1	-	
		$V_{DD}=3.3\text{ V}$, $R_m=30\Omega$, $CL=20\text{ pF}@32\text{ MHz}$	-	1.5	-	
g_m	Oscillator transconductance	Startup	10	-	-	mA/V
$t_{SU(HSE)}^{(4)}$	Startup time	V_{DD} is stabilized	-	2	-	ms

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
2. Guaranteed by design.
3. This consumption level occurs during the first 2/3 of the $t_{SU(HSE)}$ startup time.
4. $t_{SU(HSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

Low-speed internal (LSI) RC oscillator

Table 44. LSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSI}	Frequency	30	40	50	kHz
$t_{su(LSI)}^{(2)}$	LSI oscillator startup time	-	-	85	μ s
$I_{DD(LSI)}^{(2)}$	LSI oscillator power consumption	-	0.75	1.2	μ A

1. $V_{DDA} = 3.3$ V, $T_A = -40$ to 105 °C unless otherwise specified.

2. Guaranteed by design.

6.3.9 PLL characteristics

The parameters given in [Table 45](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 22](#).

Table 45. PLL characteristics

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
f_{PLL_IN}	PLL input clock ⁽¹⁾	1 ⁽²⁾	-	24 ⁽²⁾	MHz
	PLL input clock duty cycle	40 ⁽²⁾	-	60 ⁽²⁾	%
f_{PLL_OUT}	PLL multiplier output clock	16 ⁽²⁾	-	72	MHz
t_{LOCK}	PLL lock time	-	-	200 ⁽²⁾	μ s
Jitter	Cycle-to-cycle jitter	-	-	300 ⁽²⁾	ps

1. Take care of using the appropriate multiplier factors so as to have PLL input clock values compatible with the range defined by f_{PLL_OUT} .

2. Guaranteed by design.

All I/Os are CMOS and TTL compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements is shown in [Figure 19](#) and [Figure 20](#) for standard I/Os.

Figure 19. TC and TTa I/O input characteristics - CMOS port

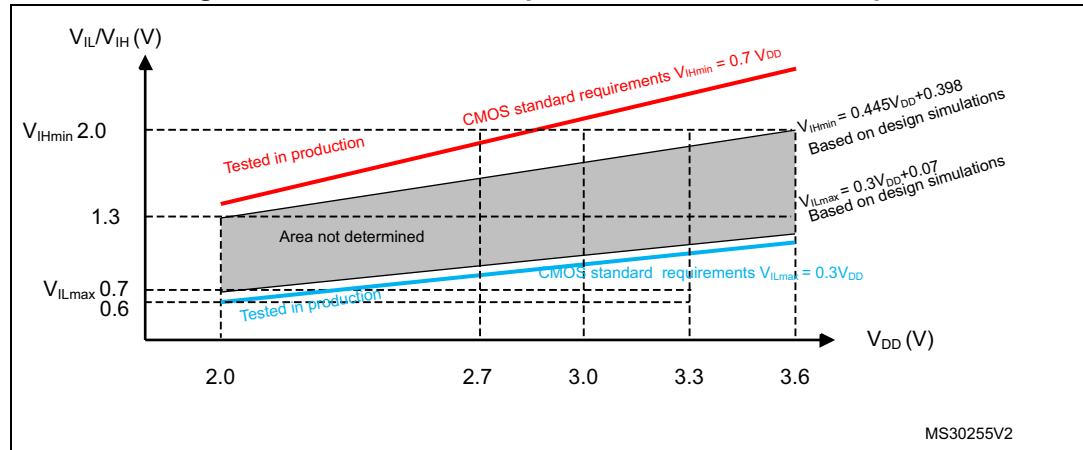


Figure 20. TC and TTa I/O input characteristics - TTL port

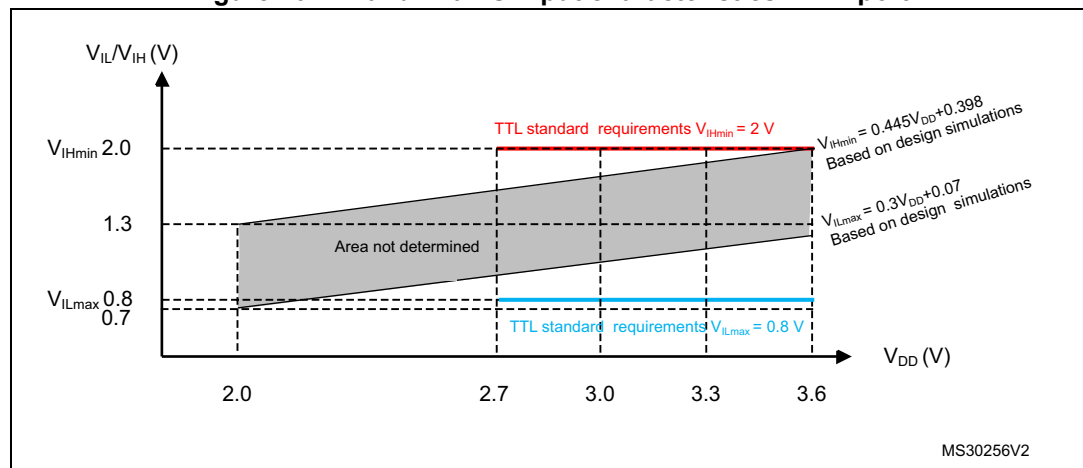


Figure 21. Five volt tolerant (FT and FTf) I/O input characteristics - CMOS port

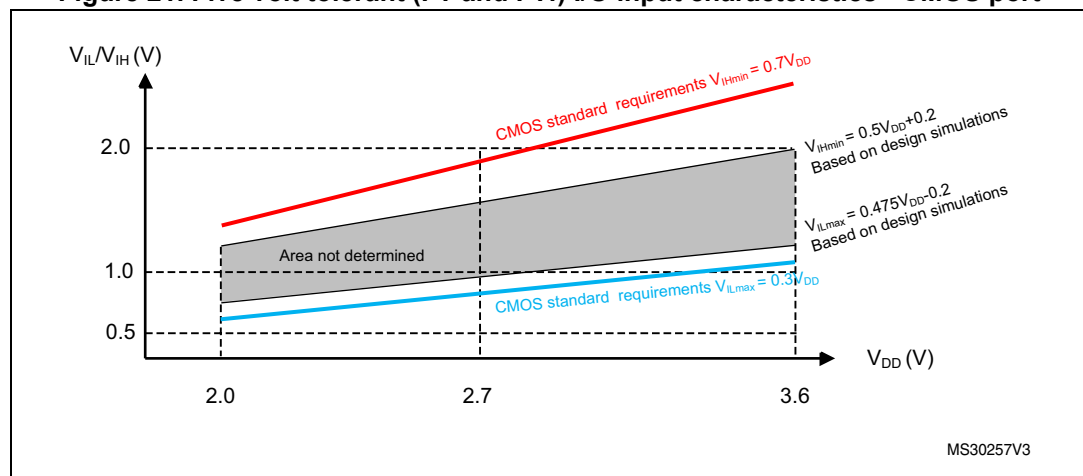
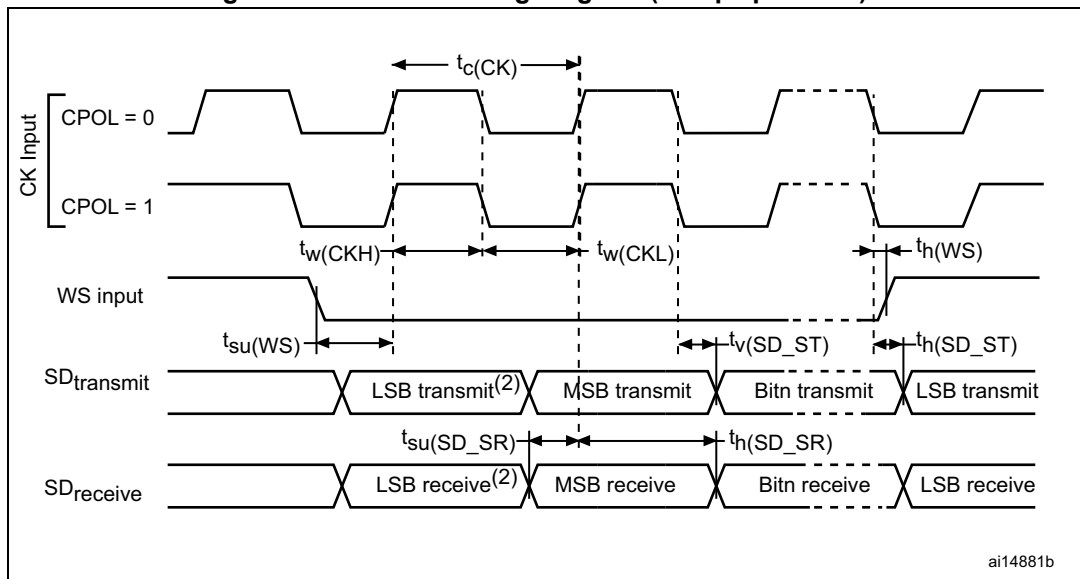
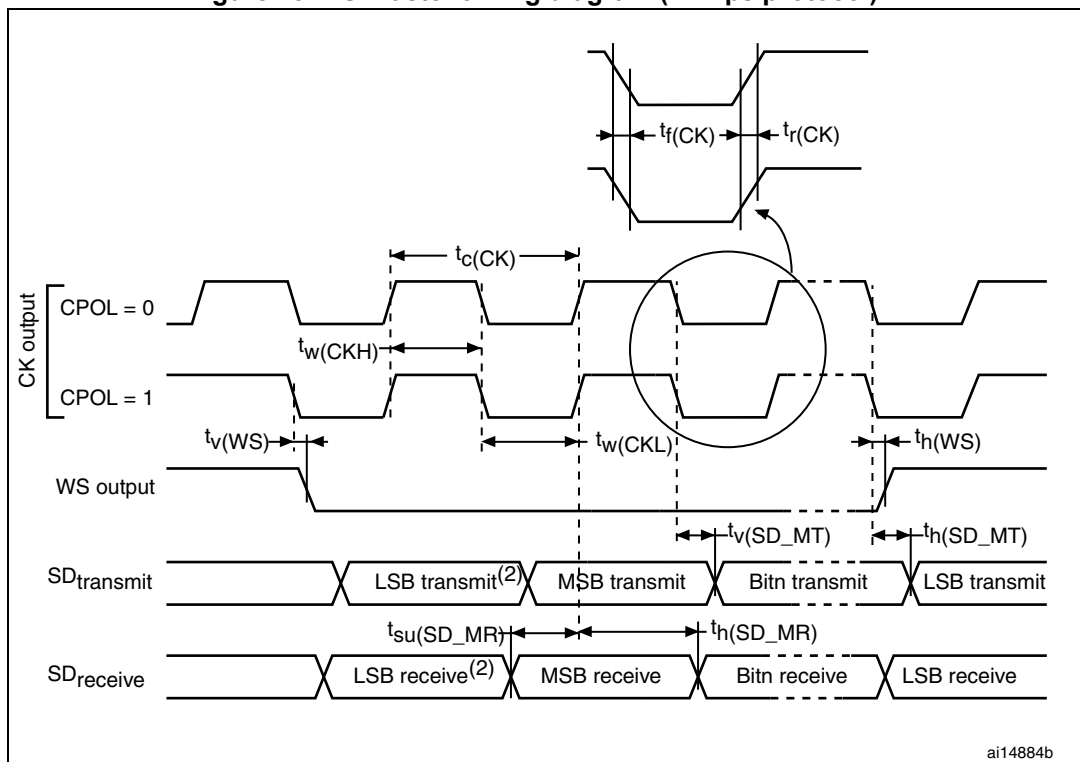


Figure 28. I²S slave timing diagram (Philips protocol)⁽¹⁾

1. Measurement points are done at 0.5V_{DD} and with external C_L=30 pF.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

Figure 29. I²S master timing diagram (Philips protocol)⁽¹⁾

1. Measurement points are done at 0.5V_{DD} and with external C_L=30 pF.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

Table 72. Comparator characteristics⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
t_{S_SC}	V_{REFINT} scaler startup time from power down	V_{REFINT} scaler activation after device power on	-	-	1 ⁽³⁾	s
		Next activations	-	-	0.2	ms
t_{START}	Comparator startup time	$V_{DDA} \geq 2.7$ V	-	-	4	μ s
		$V_{DDA} < 2.7$ V	-	-	10	
t_D	Propagation delay for 200 mV step with 100 mV overdrive	$V_{DDA} \geq 2.7$ V	-	25	28	ns
		$V_{DDA} < 2.7$ V	-	28	30	
	Propagation delay for full range step with 100 mV overdrive	$V_{DDA} \geq 2.7$ V	-	32	35	
		$V_{DDA} < 2.7$ V	-	35	40	
V_{OFFSET}	Comparator offset error	$V_{DDA} \geq 2.7$ V	-	± 5	± 10	mV
		$V_{DDA} < 2.7$ V	-	-	± 25	
TV_{OFFSET}	Total offset variation	Full temperature range	-	-	3	mV
$I_{DD(COMP)}$	COMP current consumption	-	-	400	600	μ A

1. Guaranteed by design.

2. The comparators do not have built-in hysteresis.

3. For more details and conditions, see [Figure 35: Maximum \$V_{REFINT}\$ scaler startup time from power down](#).

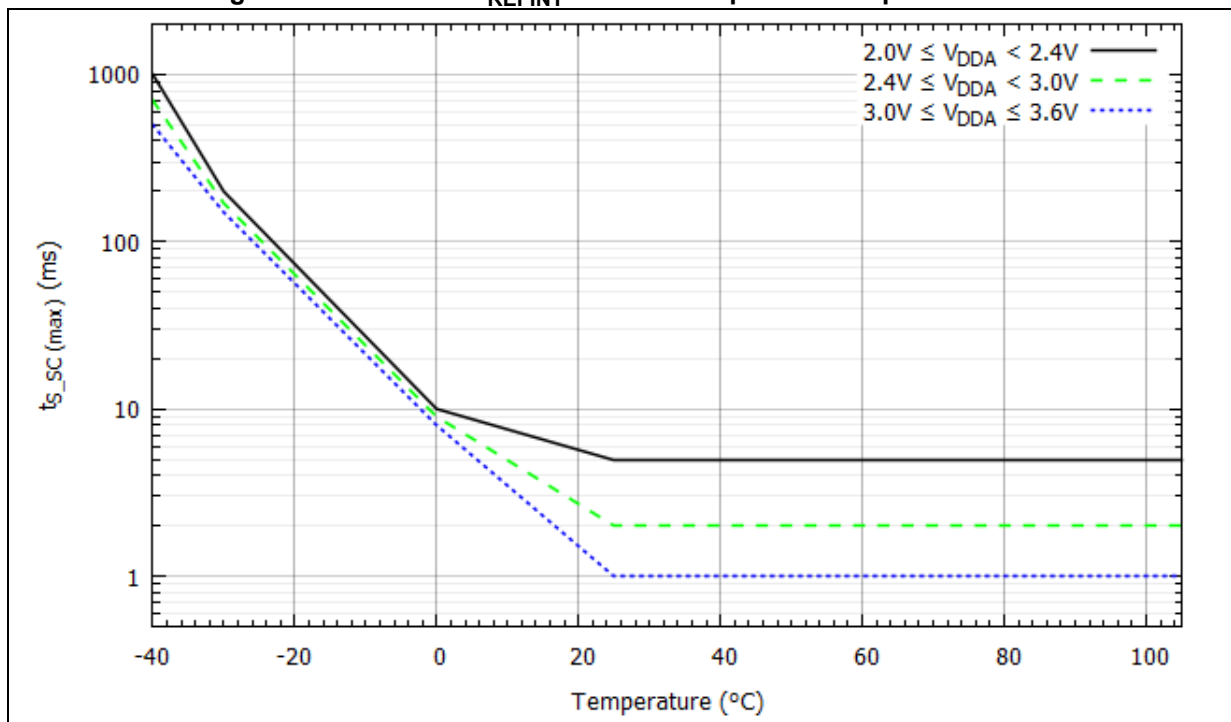
Figure 35. Maximum V_{REFINT} scaler startup time from power down

Figure 36. OPAMP Voltage Noise versus Frequency

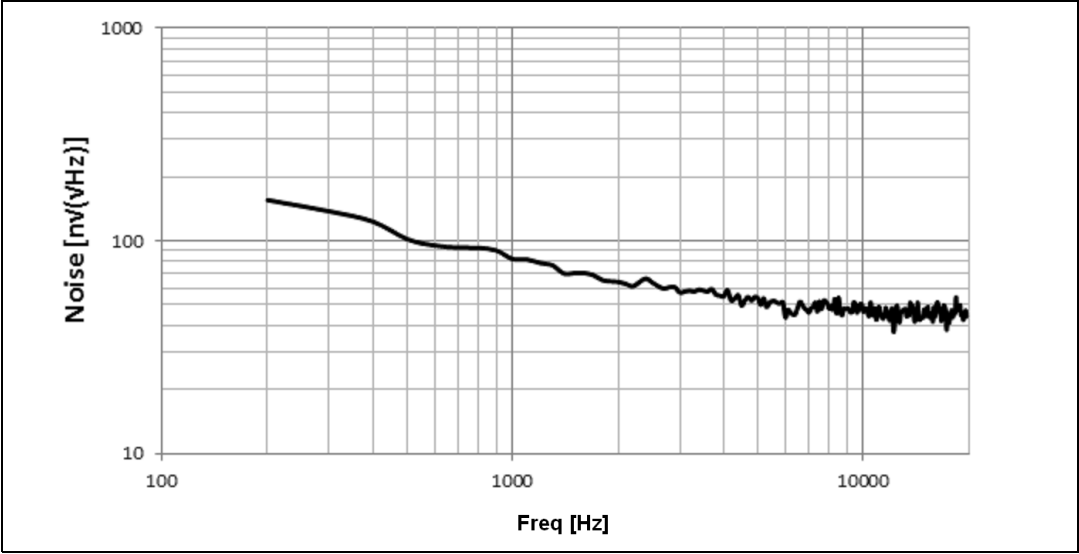
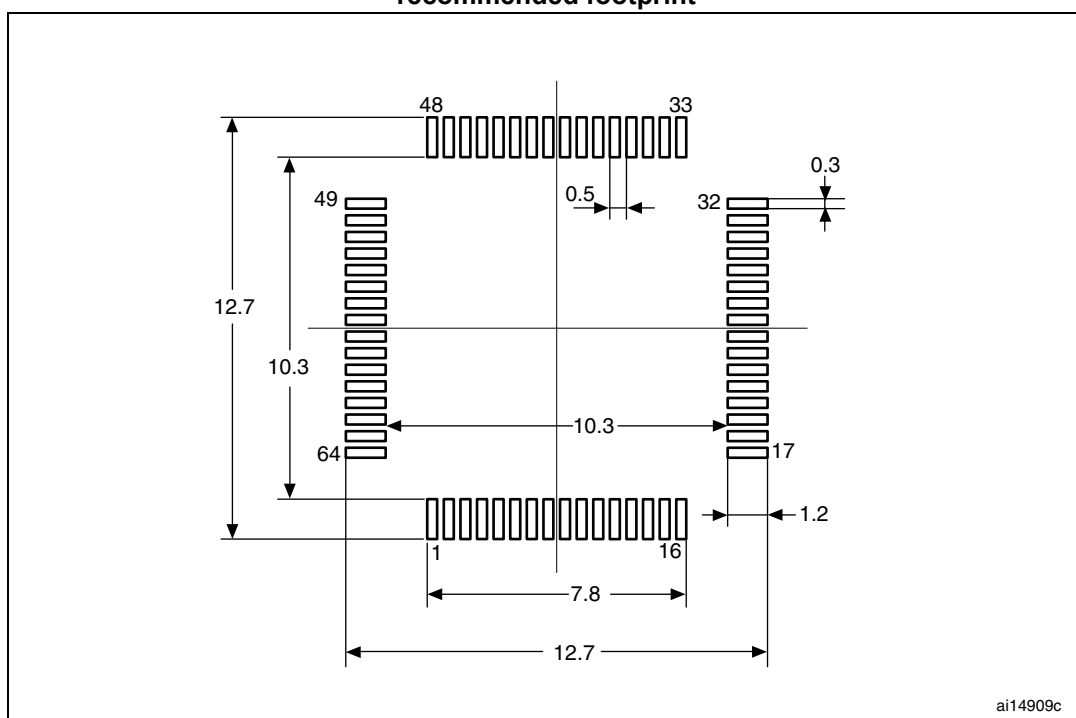


Table 79. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 41. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package recommended footprint

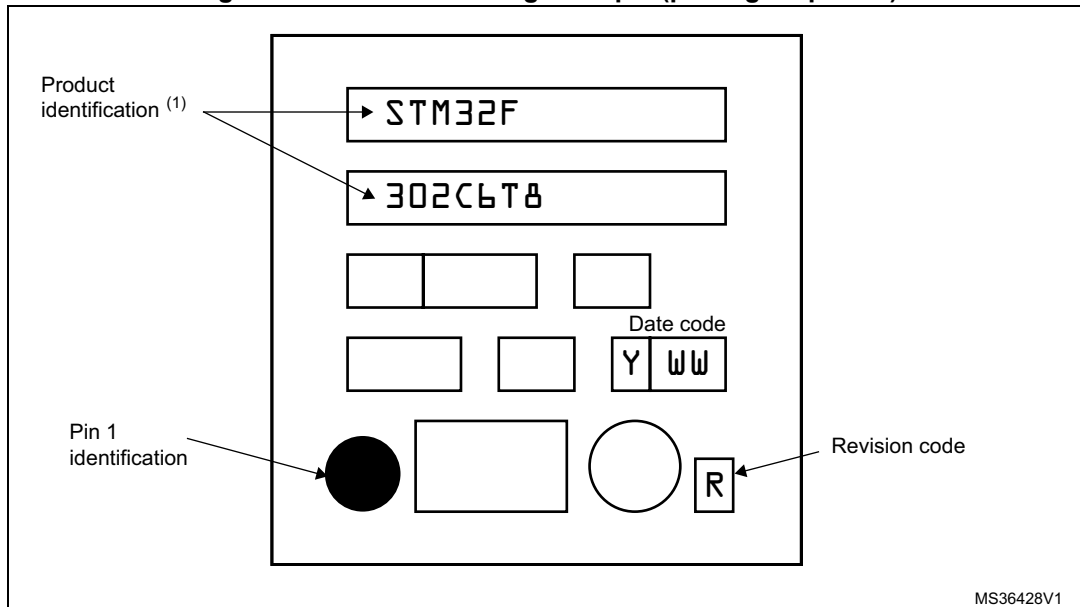


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 45. LQFP48 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

8 Ordering information

Table 83. Ordering information scheme

Example:	STM32	F	302	K	8	T	6	xxx
Device family								
STM32 = ARM®-based 32-bit microcontroller								
Product type								
F = general-purpose								
Device subfamily								
302 = STM32F302xx, 2.0 to 3.6 V operating voltage								
Pin count								
K = 32 pins								
C = 48 or 49 pins								
R = 64 pins								
Flash memory size								
6 = 32 Kbytes of Flash memory								
8 = 64 Kbytes of Flash memory								
Package								
T = LQFP								
Y= WLCSP								
U= UFQFPN								
Temperature range								
6 = Industrial temperature range, −40 to 85 °C								
7 = Industrial temperature range, −40 to 105 °C								
Options								
xxx = programmed parts								
TR = tape and reel								